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L3	289	434/308.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:19
L4	211	434/319.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:19
L5	551	434/322.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:19
L6	467	434/365.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:19
L7	78	434/401.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:20
L8	479	(3 xor 4) (3 and 4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:20
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L11	1531	(10 xor 7) (10 and 7)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:21

L12	88	434/309.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:22
L13	1592	(11 xor 12) (11 and 12)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:22
L14	31	434/310.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:23
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L26	2182	(25 xor 20) (25 and 20)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:26
L27	2480	(26 xor 21) (26 and 21)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:30
L28	2992326	transmi\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:31
L29	621797	instruct\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:31
L30	280008	28 and 29	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:31
L31	115878	28 same 29	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:33

L32	658116	remote	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:35
L33	4949	classroom\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:35
L34	30762	student\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:37
L35	230425	moderat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:37
L36	2065801	degree\$1 diploma\$1 certificate\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:38
L37	2555	31.tl.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:39
L38	2	"5727950".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:39
L39	7	("4785472" "5535422" "5493658" "5442759" "5850250" "5833468" "6014134").pn.	USPAT	OR	ON	2004/12/30 16:39
L40	9	L38 xor L39 L38 and L39	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:42
L41	0	37 and 40	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:53

L42	3	31 and 40	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:55
L43	0	37 and 27	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:54
L44	57	32 and 33 and 34 and 35 and 36	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 16:55
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L2	1	MATHARU-NAVTEJ.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 14:00
L3	0	MALHOTRA-RAMESH.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 13:56
L4	13548	cook.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 14:02
L5	2	"5727950".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 14:03
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L7	21110680	@ad<="20010824"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 14:13

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Dang, A.X.H.; Ebert-Uphoff, I.;

Robotics, IEEE Transactions on [see also Robotics and Automation, IEEE Transactions on] ,Volume: 20 , Issue: 5 , Oct. 2004

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[\[Abstract\]](#) [\[PDF Full-Text \(1288KB\)\]](#) **IEEE JNL**
2 Process induced warpage in multitiled alumina substrates for large MCM-D processing
Dang, A.X.H.; Ume, I.C.; Bhattacharya, S.K.;

Advanced Packaging, IEEE Transactions on [see also Components, Packaging Manufacturing Technology, Part B: Advanced Packaging, IEEE Transactions on] ,Volume: 23 , Issue: 3 , Aug. 2000

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3 Warpage measurement of large area multitilted silicon substrates at various processing conditions
Bhattacharya, S.K.; Ume, I.C.; Dang, A.X.H.;

Components and Packaging Technologies, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part A: Packaging Technologies, IEEE Transactions on] ,Volume: 23 , Issue: 3 , Sept. 2000

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2 Process induced warpage in multitiled alumina substrates for large : MCM-D processing*Dang, A.X.H.; Ume, I.C.; Bhattacharya, S.K.;*

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3 Warpage measurement of large area multitilted silicon substrates at various processing conditions*Bhattacharya, S.K.; Ume, I.C.; Dang, A.X.H.;*

Components and Packaging Technologies, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part A: Packaging Technologies, IEEE Transactions on] ,Volume: 23 , Issue: 3 , Sept. 2000

Pages:497 - 504

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4 Motion planning for active acceleration compensation*Decker, M.W.; Dang, A.X.; Ebert-Uphoff, I.;*

Robotics and Automation, 2001. Proceedings 2001 ICRA. IEEE International Conference on ,Volume: 2 , 2001

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1 Three Dimensional Structure Of A Natural Autoantibody A Predicted Model Of The Antigen Binding Site.
Dang, A.M.; Raveche, E.;

Engineering in Medicine and Biology Society, 1992. Vol.14. Proceedings of the Annual International Conference of the IEEE ,Volume: 1 , October 29- November 1, 1992

Pages:202 - 203

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1 Learning sensor-detection policies
Malhotra, R.; Blasch, E.P.; Johnson, J.D.;

 Aerospace and Electronics Conference, 1997. NAECON 1997., Proceedings of 1
 IEEE 1997 National ,Volume: 2 , 14-17 July 1997

Pages:769 - 776 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(700KB\)\]](#) **IEEE CNF**
2 Convergence behavior of temporal difference learning
Malhotra, R.P.;

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[\[Abstract\]](#) [\[PDF Full-Text \(416KB\)\]](#) **IEEE CNF**
3 Project management challenges of high technology product develop
Temponi, C.; Malhotra, R.;

 Engineering Management Conference, 2002. IEMC '02. 2002 IEEE Internation:
 ,Volume: 1 , 2002

Pages:356 - 361 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(506KB\)\]](#) **IEEE CNF**
4 Role of multiresolution attention in automated object recognition
Iftexharuddin, K.M.; Malhotra, R.P.;

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Pages:2255 - 2260

[\[Abstract\]](#) [\[PDF Full-Text \(709KB\)\]](#) **IEEE CNF**
5 Graph-theoretic networks for holistic information fusion
Malhotra, R.P.; Yufik, Y.M.;

 Neural Networks, 1999. IJCNN '99. International Joint Conference on ,Volume:
 4 , 10-16 July 1999

Pages:2796 - 2801 vol.4

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6 Temporal considerations in sensor management

Malhotra, R.;

Aerospace and Electronics Conference, 1995. NAECON 1995., Proceedings of the IEEE 1995 National , Volume: 1 , 22-26 May 1995

Pages:86 - 93 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(912KB\)\]](#) [IEEE CNF](#)

7 Optical computing for artificial neural network implementations

Malhotra, R.;

Aerospace and Electronics Conference, 1994. NAECON 1994., Proceedings of the IEEE 1994 National , 23-27 May 1994

Pages:779 - 786 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(604KB\)\]](#) [IEEE CNF](#)

8 A dynamic, nonlinear model for optimal decision-making

Malhotra, R.;

Aerospace and Electronics Conference, 1994. NAECON 1994., Proceedings of the IEEE 1994 National , 23-27 May 1994

Pages:1325 - 1329 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(392KB\)\]](#) [IEEE CNF](#)

9 Chasing the elusive sensor manager

Musick, S.; Malhotra, R.;

Aerospace and Electronics Conference, 1994. NAECON 1994., Proceedings of the IEEE 1994 National , 23-27 May 1994

Pages:606 - 613 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(740KB\)\]](#) [IEEE CNF](#)

10 Evaluation of electronic artificial neural network implementations

Malhotra, R.P.; Siferd, R.;

Aerospace and Electronics Conference, 1993. NAECON 1993., Proceedings of the IEEE 1993 National , 24-28 May 1993

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